

Specification of Automotive MLCC

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor
- Samsung P/N : **CL21B103KB65PNC**

• AEC-Q 200 Specified

CAP, 10nF, 50V, ±10%, X7R, 0805 • Description :

Cardboard Type, 7" reel

A. Samsung Part Number

€

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Thickness

<u>CL</u> <u>21</u> 103 <u>P</u> <u>C</u> B <u>K</u> B <u>6</u> <u>5</u> Ν 1 2 3 4 5 6 1 8 9 10 1 Series Samsung Multi-layer Ceramic Capacitor 2 Size 0805 (inch code) L: 2.0 ± 0.1 mm W: 1.25 ± 0.1 mm **③** Dielectric X7R (8) Inner electrode Ni, Open mode **④** Capacitance 10 nF Termination Cu, Ag-epoxy **⑤** Capacitance ±10 % Plating Sn 100% (Pb Free) tolerance **9** Product Automotive Grade code Standard 6 Rated Voltage 50 V (10)

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Packaging

B. Reliablility Test and Judgement condition

0.6 ± 0.1

mm

	Performance	Test condition
High Temperature	Appearance : No abnormal exterior appearance	Unpowered, 1000hrs@T=150℃
Exposure	Capacitance Change : Within ±10%	Measurement at 24±2hrs after test conclusion
	Tan δ: 0.03 max	
	IR : More than 10,000 Ω or 500 $\Omega \times \mu F$	
	Whichever is Smaller	
Temperature Cycling	Appearance : No abnormal exterior appearance	1000Cycles
	Capacitance Change : Within ±10%	Measurement at 24±2hrs after test conclusion
	Tan δ: 0.03 max	1 cycle condition :
	IR : More than 10,000 or 500 M × μ F	-55+0/-3℃(15±3min) -> Room Temp(1min.)
	Whichever is Smaller	-> 125+3/-0℃(15±3min) -> Room Temp(1min.)
Destructive Physical	No Defects or abnormalities	Per EIA 469
Analysis		
Moisture Resistance	Appearance : No abnormal exterior appearance	10Cycles, t=24hrs/cycle
	Capacitance Change : Within ±12.5%	Heat (25~65 $^\circ C$) and humidity (80~98%), Unpowered
	Tan δ: 0.03 max	measurement at 24±2hrs after test conclusion
	IR : More than 10,000 or 500 M × μ F	
	Whichever is Smaller	
Humidity Bias	Appearance : No abnormal exterior appearance	1000hrs 85 $^{\circ}$ C/85%RH, Rated Voltate and 1.3~1.5V,
	Capacitance Change : Within ±12.5%	Add 100kohm resistor
	Tan δ: 0.035 max	Measurement at 24±2hrs after test conclusion
	IR : More than 500MΩ or 25 MΩ× μ F	The charge/discharge current is less than 50mA.
	Whichever is Smaller	
High Temperature	Appearance : No abnormal exterior appearance	1000hrs @ TA=125℃, 200% Rated Voltage,
Operating Life	Capacitance Change : Within ±12.5%	Measurement at 24±2hrs after test conclusion
	Tan δ: 0.035 max	The charge/discharge current is less than 50mA.
	IR : More than 1000MΩ or 50MΩ× μ F	
	Whichever is Smaller	

	Performance	Test condition
External Visual	No abnormal exterior appearance	Microscope ('10)
Physical Dimensions	Within the specified dimensions	Using The calipers
Filysical Dimensions		
Mechanical Shock	Appearance : No abnormal exterior appearance	Three shocks in each direction should be applied along
	Capacitance Change : Within ±10%	3 mutually perpendicular axes of the test specimen (18 shocks)
	Tan δ, IR : initial spec.	Peakvalue Duration Wave Velocity
		1,500G 0.5ms Half sine 4.7m/sec.
Vibration	Appearance : No abnormal exterior appearance	5g's for 20min., 12cycles each of 3 orientations,
	Capacitance Change : Within ±10%	Use 8"×5" PCB 0.031" Thick 7 secure points on one long side
	Tan δ, IR : initial spec.	and 2 secure points at corners of opposite sides. Parts mounted
		within 2" from any secure point. Test from 10~2000 ${ m Hz}$.
Resistance to	Appearance : No abnormal exterior appearance	Solder pot : 260±5℃, 10±1sec.
Solder Heat	Capacitance Change : Within ±10%	
	Tan δ, IR : initial spec.	
Thermal Shock	Appearance : No abnormal exterior appearance	-55℃/+125℃.
	Capacitance Change : Within ±10%	Note: Number of cycles required-300,
	Tan δ, IR : initial spec.	Maximum transfer time-20 sec, Dwell time-15min. Air-Air
ESD	Appearance : No abnormal exterior appearance	AEC-Q200-002
	Capacitance Change : Within ±10%	
	Tan δ, IR : initial spec.	
Solderability	95% of the terminations is to be soldered	a) Preheat at 155 $^\circ C$ for 4 hours, Immerse in solder for 5s at 245±5 $^\circ C$
	evenly and continuously	b) Steam aging for 8 hours, Immerse in solder for 5s at $245\pm5^\circ\!\!\mathrm{C}$
		c) Steam aging for 8 hours, Immerse in solder for 120s at 260 $\pm5^\circ\!\mathrm{C}$
		solder : a solution ethanol and rosin
Electrical	Capacitance : Within specified tolerance	The Capacitance /D.F. should be measured at $25^\circ\!\!\mathrm{C}$,
Characterization	Tan δ (DF)0.025 max.	1㎞±10%, 1.0±0.2Vrms
	IR(25℃) : More than 10,000№ or 500№×µF	I.R. should be measured with a DC voltage not exceeding
	$IR(125^{\circ}C)$: More than 1,000M Ω or 10M $\Omega \times \mu F$	Rated Voltage @25℃, @125℃ for 60~120 sec.
	Whichever is Smaller	
	Dielectric Strength	Dielectric Strength : 250% of the rated voltage for 1~5 seconds
Board Flex	Appearance : No abnormal exterior appearance	Bending to the limit (2mm) for 5 seconds
	Capacitance Change : Within ±10%	
Terminal	Appearance : No abnormal exterior appearance	18N, for 60±1 sec.
Strength(SMD)	Capacitance Change : Within ±10%	
Beam Load	Destruction value should not be exceed	Beam speed
	Chip Length < 2.5mm	0.5±0.05mm/sec
	a) Chip Thickness > 0.5mm : 20N	
	b) Chip Thickness \leq 0.5mm : 8N	
Temperature	X7R	
Characterisitcs	(From -55℃ to 125℃, Capacitance change sho	ud be within ±15%)

C. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260+0/-5 $^\circ C$, 10sec. Max) Meet IPC/JEDEC J-STD-020 D Standard

* For the more detail Specification, Please refer to the Samsung MLCC catalogue.